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Attorney Docket No. H1938

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: :  
Zoran Krivokapic : Group Art Unit: 2812  
Serial No.: 10/601,401 : Examiner: Not yet assigned  
Filed: June 23, 2003 :

Title: SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURE

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

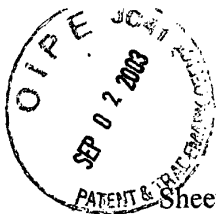
Sir:

Attached hereto is a completed Form PTO-1449 listing patents, publications, or other information which the applicant believes may be material to the examination of this application, with copies of each such item enclosed herewith. It is requested that the cited patents be made of record in the examination of this application. This information disclosure statement is being filed prior to the first Office Action and no certification or fee is required. The Commissioner is authorized to charge any fee deficiency required by this paper or credit any overpayment to Deposit Account No. 50-2173. A duplicate of this communication is enclosed.

Respectfully submitted,

Dated: 29 August 2003

By Rennie William Dover  
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Sheet 1 of 1

<b>FORM PTO-1449</b>  <b>U.S. DEPARTMENT OF COMMERCE</b>  <b>PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)	<b>ATTY. DOCKET NO.</b> H1938	<b>SERIAL NO</b> 10/601,401
	<b>APPLICANT</b> Zoran Krivokapic	
	<b>FILING DATE</b> June 23, 2003	<b>GROUP</b> 2812

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS (Including Author, Title, Date Pertinent Pages, Etc.)**

		M.V. Fischetti and S.E. Laux, Band structure, deformation potentials, and carrier mobility in strained Si, Ge, and SiGe alloys, Thomas J. Watson Research Center, J.Appl. Phys. 80(4), 15 August 1996, pp. 2234-2252.

**EXAMINER****DATE  
CONSIDERED**

**EXAMINER:** Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.